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Application/Control No.	Applicant(s)/Patent under Reexamination		
09/805,887	LAROIA ET AL.		
Examiner	Art Unit		
Steven HD Nguyen	2665		

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SEARCHED				
Class	Subclass	Date	Examiner	
370	203-210	7/5/2005	ST	
375	260-261			
	270, 296			
•	298, 301			
	346, 348	•		
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INTERFERENCE SEARCHED				
Subclass	Date	Examiner-		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST IFFT and Interpolator	7/5/2005	ST
East test Scarch	12/16/06	87
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